

## DIGITAL AUDIO MOSFET

### Features

- Integrated Half-Bridge Package
- Reduces the Part Count by Half
- Facilitates Better PCB Layout
- Key Parameters Optimized for Class-D Audio Amplifier Applications
- Low  $R_{DS(ON)}$  for Improved Efficiency
- Low  $Q_g$  and  $Q_{sw}$  for Better THD and Improved Efficiency
- Low  $Q_{rr}$  for Better THD and Lower EMI
- Can Delivery up to 200W per Channel into  $8\Omega$  Load in Half-Bridge Configuration Amplifier
- Lead-Free Package

| Key Parameters ⑥        |     |             |
|-------------------------|-----|-------------|
| $V_{DS}$                | 150 | V           |
| $R_{DS(ON)}$ typ. @ 10V | 80  | m $\Omega$  |
| $Q_g$ typ.              | 13  | nC          |
| $Q_{sw}$ typ.           | 4.1 | nC          |
| $R_{G(int)}$ typ.       | 2.5 | $\Omega$    |
| $T_J$ max               | 150 | $^{\circ}C$ |



| G1, G2 | D1, D2 | S1, S2 |
|--------|--------|--------|
| Gate   | Drain  | Source |

### Description

This Digital Audio MosFET Half-Bridge is specifically designed for Class D audio amplifier applications. It consists of two power MosFET switches connected in half-bridge configuration. The latest process is used to achieve low on-resistance per silicon area. Furthermore, Gate charge, body-diode reverse recovery, and internal Gate resistance are optimized to improve key Class D audio amplifier performance factors such as efficiency, THD and EMI. These combine to make this Half-Bridge a highly efficient, robust and reliable device for Class D audio amplifier applications.

### Absolute Maximum Ratings ⑥

|                              | Parameter   | Max.             | Units          |
|------------------------------|---|------------------|----------------|
| $V_{DS}$                     | Drain-to-Source Voltage                                 | 150              | V              |
| $V_{GS}$                     | Gate-to-Source Voltage                                  | $\pm 20$         |                |
| $I_D$ @ $T_C = 25^{\circ}C$  | Continuous Drain Current, $V_{GS}$ @ 10V                | 8.7              | A              |
| $I_D$ @ $T_C = 100^{\circ}C$ | Continuous Drain Current, $V_{GS}$ @ 10V                | 6.2              |                |
| $I_{DM}$                     | Pulsed Drain Current ①                                  | 34               |                |
| $E_{AS}$                     | Single Pulse Avalanche Energy ②                         | 77               | mJ             |
| $P_D$ @ $T_C = 25^{\circ}C$  | Power Dissipation ④                                     | 18               | W              |
| $P_D$ @ $T_C = 100^{\circ}C$ | Power Dissipation ④                                     | 7.2              |                |
|                              | Linear Derating Factor                                  | 0.15             | W/ $^{\circ}C$ |
| $T_J$<br>$T_{STG}$           | Operating Junction and Storage Temperature Range        | -55 to + 150     | $^{\circ}C$    |
|                              | Soldering Temperature, for 10 seconds (1.6mm from case) | 300              |                |
|                              | Mounting torque, 6-32 or M3 screw                       | 10lb·in (1.1N·m) |                |

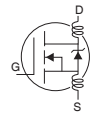
### Thermal Resistance ⑥

|                 | Parameter             | Typ. | Max. | Units |
|-----------------|-----------------------|------|------|-------|
| $R_{\theta JC}$ | Junction-to-Case ④    | —    | 6.9  |       |
| $R_{\theta JA}$ | Junction-to-Ambient ④ | —    | 65   |       |

Notes ① through ⑥ are on page 2

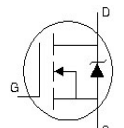
## Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified) ⑥

|                                | Parameter                            | Min. | Typ. | Max. | Units               | Conditions   |
|--------------------------------|--------------------------------------|------|------|------|---------------------|--|
| $BV_{DSS}$                     | Drain-to-Source Breakdown Voltage    | 150  | —    | —    | V                   | $V_{GS} = 0V, I_D = 250\mu A$  |
| $\Delta BV_{DSS}/\Delta T_J$   | Breakdown Voltage Temp. Coefficient  | —    | 0.19 | —    | $V/^\circ\text{C}$  | Reference to $25^\circ\text{C}, I_D = 1\text{mA}$  |
| $R_{DS(on)}$                   | Static Drain-to-Source On-Resistance | —    | 80   | 95   | $m\Omega$           | $V_{GS} = 10V, I_D = 5.2A$ ③   |
| $V_{GS(th)}$                   | Gate Threshold Voltage               | 3.0  | —    | 4.9  | V                   | $V_{DS} = V_{GS}, I_D = 50\mu A$   |
| $\Delta V_{GS(th)}/\Delta T_J$ | Gate Threshold Voltage Coefficient   | —    | -11  | —    | $mV/^\circ\text{C}$ |  |
| $I_{DSS}$                      | Drain-to-Source Leakage Current      | —    | —    | 20   | $\mu A$             | $V_{DS} = 150V, V_{GS} = 0V$   |
|                                |                                      | —    | —    | 250  |                     | $V_{DS} = 150V, V_{GS} = 0V, T_J = 125^\circ\text{C}$  |
| $I_{GSS}$                      | Gate-to-Source Forward Leakage       | —    | —    | 100  | nA                  | $V_{GS} = 20V$   |
|                                | Gate-to-Source Reverse Leakage       | —    | —    | -100 |                     | $V_{GS} = -20V$  |
| $g_{fs}$                       | Forward Transconductance             | 11   | —    | —    | S                   | $V_{DS} = 50V, I_D = 5.2A$   |
| $Q_g$                          | Total Gate Charge                    | —    | 13   | 20   | nC                  | $V_{DS} = 75V$<br>$V_{GS} = 10V$<br>$I_D = 5.2A$<br>See Fig. 6 and 19                                      |
| $Q_{gs1}$                      | Pre-Vth Gate-to-Source Charge        | —    | 3.3  | —    |                     |  |
| $Q_{gs2}$                      | Post-Vth Gate-to-Source Charge       | —    | 0.8  | —    |                     |  |
| $Q_{gd}$                       | Gate-to-Drain Charge                 | —    | 3.9  | —    |                     |  |
| $Q_{godr}$                     | Gate Charge Overdrive                | —    | 5.0  | —    |                     |  |
| $Q_{sw}$                       | Switch Charge ( $Q_{gs2} + Q_{gd}$ ) | —    | 4.1  | —    |                     |  |
| $R_{G(int)}$                   | Internal Gate Resistance             | —    | 2.5  | —    | $\Omega$            |  |
| $t_{d(on)}$                    | Turn-On Delay Time                   | —    | 7.0  | —    | ns                  | $V_{DD} = 75V, V_{GS} = 10V$ ③<br>$I_D = 5.2A$<br>$R_G = 2.4\Omega$  |
| $t_r$                          | Rise Time                            | —    | 6.6  | —    |                     |  |
| $t_{d(off)}$                   | Turn-Off Delay Time                  | —    | 13   | —    |                     |  |
| $t_f$                          | Fall Time                            | —    | 3.1  | —    |                     |  |
| $C_{iss}$                      | Input Capacitance                    | —    | 810  | —    | pF                  | $V_{GS} = 0V$<br>$V_{DS} = 25V$<br>$f = 1.0\text{MHz}$ , See Fig.5<br>$V_{GS} = 0V, V_{DS} = 0V$ to $120V$ |
| $C_{oss}$                      | Output Capacitance                   | —    | 100  | —    |                     |  |
| $C_{rfs}$                      | Reverse Transfer Capacitance         | —    | 15   | —    |                     |  |
| $C_{oss}$                      | Effective Output Capacitance         | —    | 97   | —    |                     |  |
| $L_D$                          | Internal Drain Inductance            | —    | 4.5  | —    | nH                  | Between lead,<br>6mm (0.25in.)<br>from package<br>and center of die contact                                |
| $L_S$                          | Internal Source Inductance           | —    | 7.5  | —    |                     |  |



## Diode Characteristics ⑥

|                                | Parameter                                 | Min. | Typ. | Max. | Units | Conditions  |
|--------------------------------|---|------|------|------|-------|---|
| $I_S @ T_C = 25^\circ\text{C}$ | Continuous Source Current<br>(Body Diode) | —    | —    | 8.7  | A     | MOSFET symbol<br>showing the<br>integral reverse<br>p-n junction diode. |
| $I_{SM}$                       | Pulsed Source Current<br>(Body Diode) ①   | —    | —    | 34   |       |   |
| $V_{SD}$                       | Diode Forward Voltage                     | —    | —    | 1.3  | V     | $T_J = 25^\circ\text{C}, I_S = 5.2A, V_{GS} = 0V$ ③                     |
| $t_{rr}$                       | Reverse Recovery Time                     | —    | 57   | 86   | ns    | $T_J = 25^\circ\text{C}, I_F = 5.2A$                                    |
| $Q_{rr}$                       | Reverse Recovery Charge                   | —    | 140  | 210  | nC    | $di/dt = 100A/\mu s$ ③  |



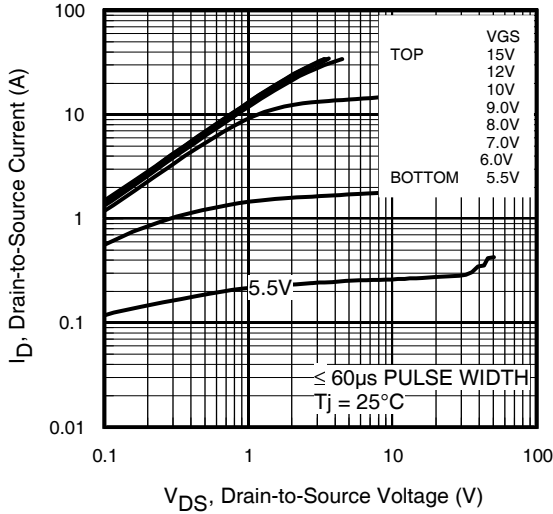
### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Starting  $T_J = 25^\circ\text{C}$ ,  $L = 5.8\text{mH}$ ,  $R_G = 25\Omega$ ,  $I_{AS} = 5.2A$ .
- ③ Pulse width  $\leq 400\mu s$ ; duty cycle  $\leq 2\%$ .

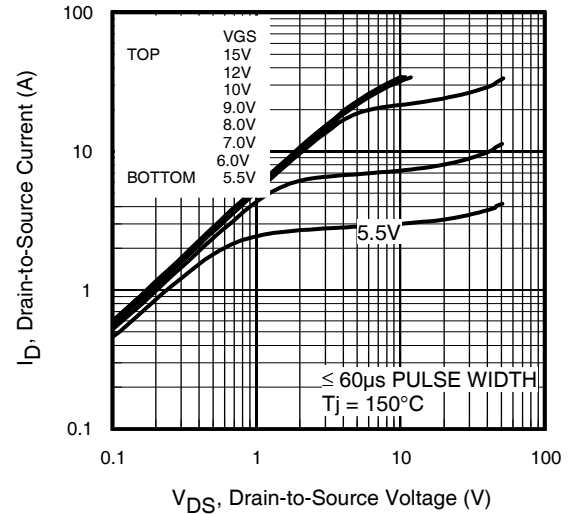
④  $R_{\theta}$  is measured at  $T_J$  of approximately  $90^\circ\text{C}$ .

⑤ Limited by  $T_{jmax}$ . See Figs. 14, 15, 17a, 17b for repetitive avalanche information

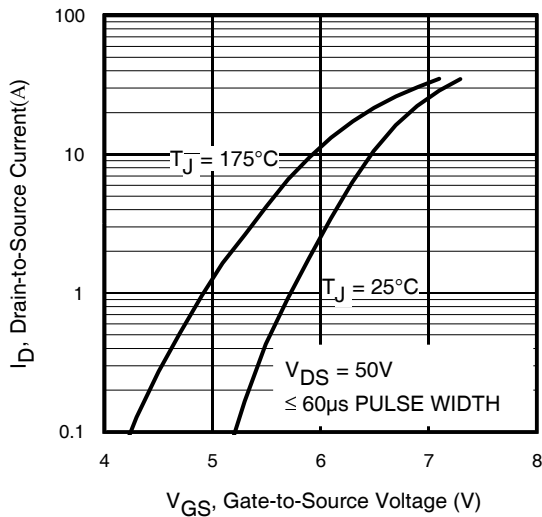
⑥ Specifications refer to single MosFET.



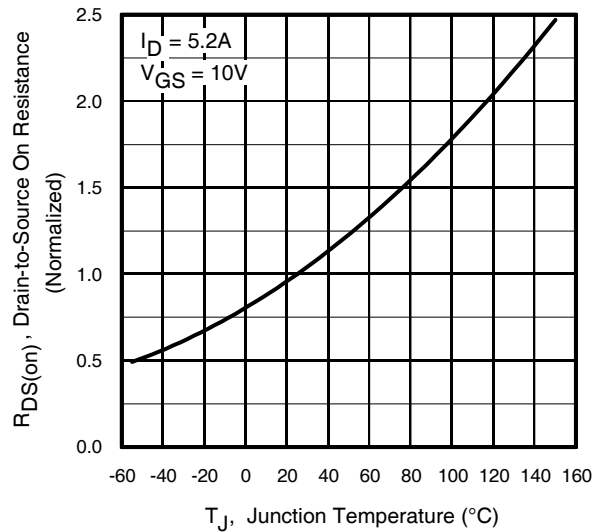
**Fig 1.** Typical Output Characteristics



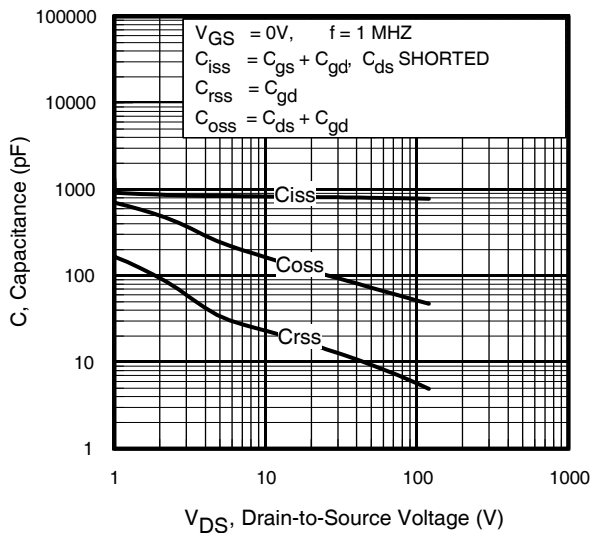
**Fig 2.** Typical Output Characteristics



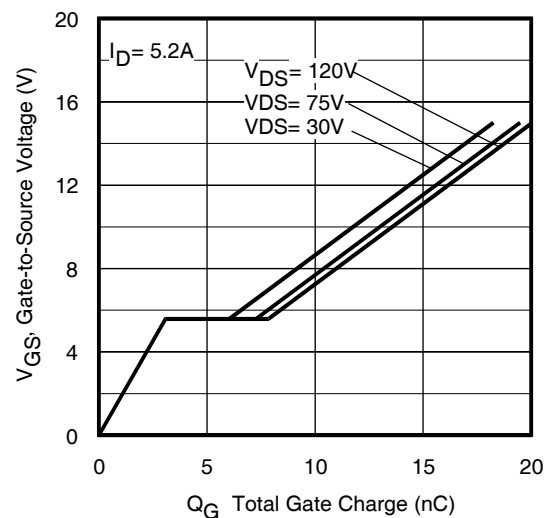
**Fig 3.** Typical Transfer Characteristics



**Fig 4.** Normalized On-Resistance vs. Temperature

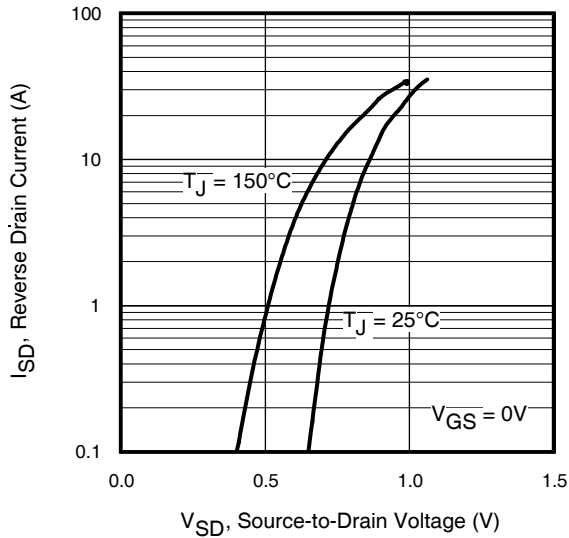


**Fig 5.** Typical Capacitance vs. Drain-to-Source Voltage  
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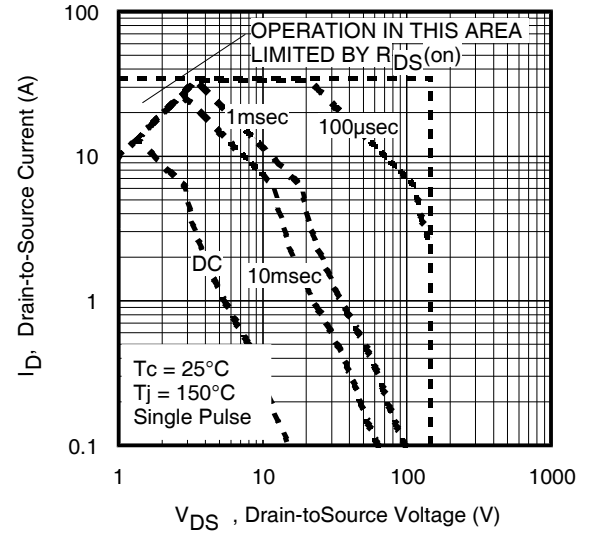


**Fig 6.** Typical Gate Charge vs. Gate-to-Source Voltage  
3

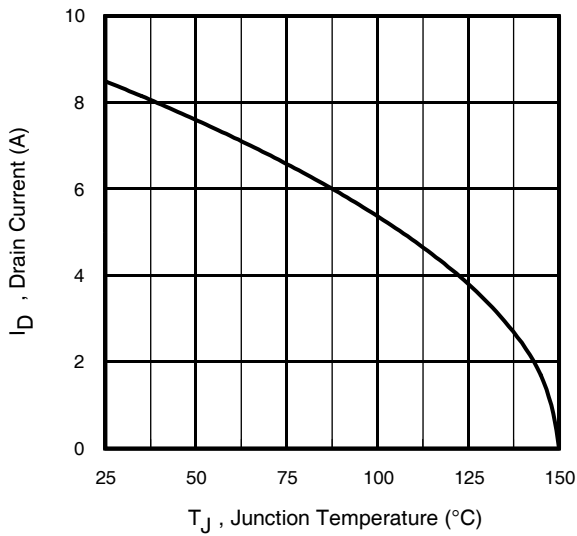
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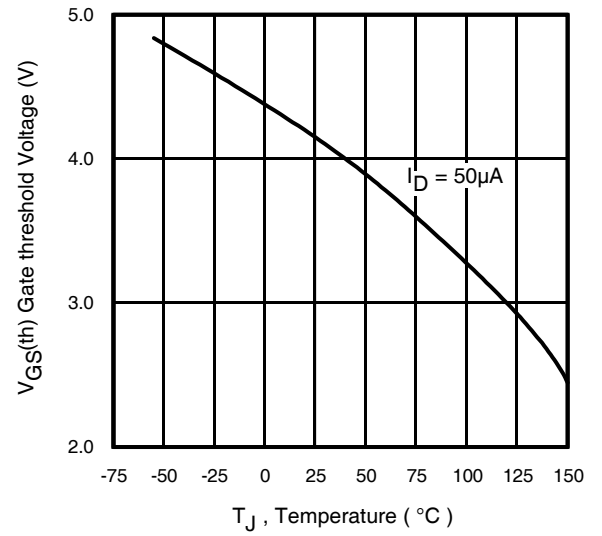
**Fig 7.** Typical Source-Drain Diode Forward Voltage



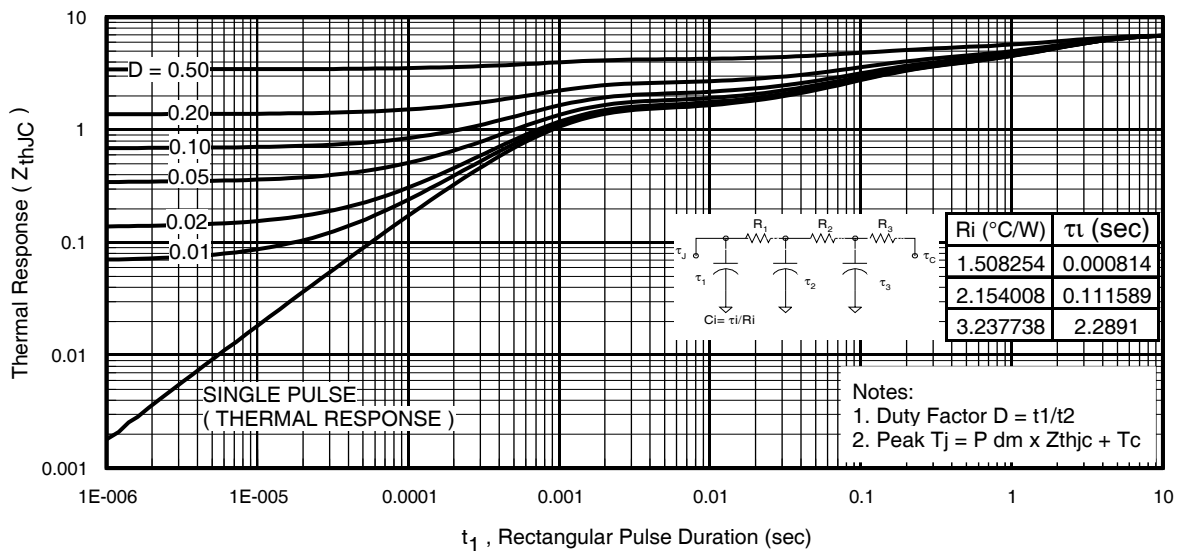
**Fig 8.** Maximum Safe Operating Area



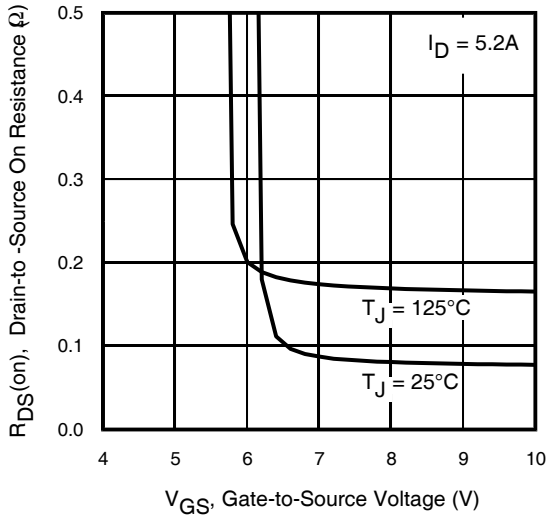
**Fig 9.** Maximum Drain Current vs. Case Temperature



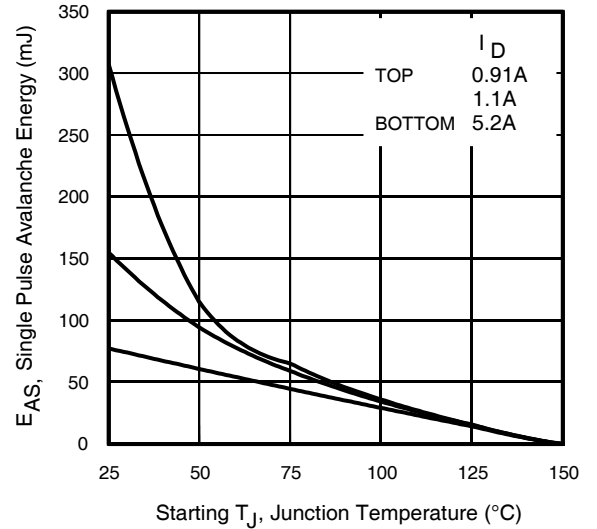
**Fig 10.** Threshold Voltage vs. Temperature



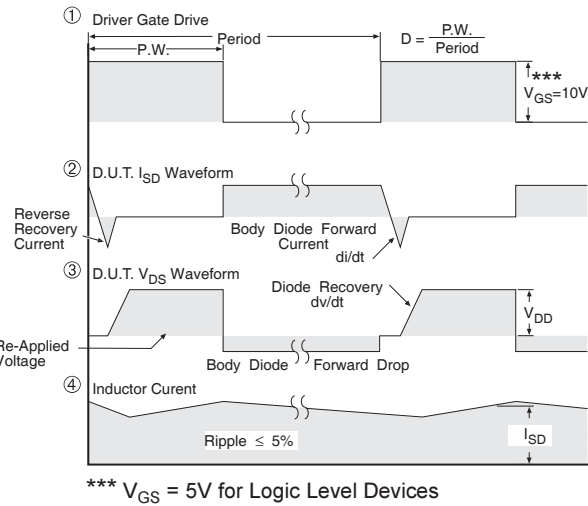
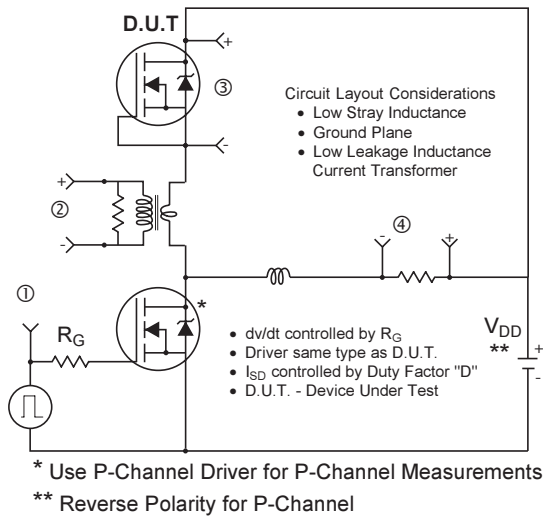
**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Case



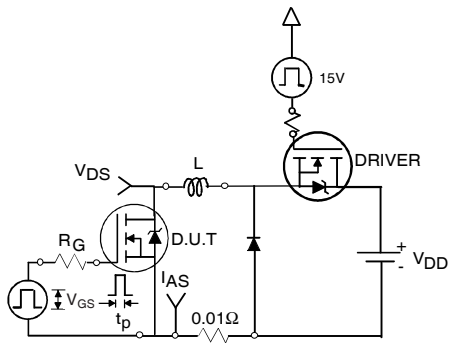
**Fig 12.** On-Resistance Vs. Gate Voltage



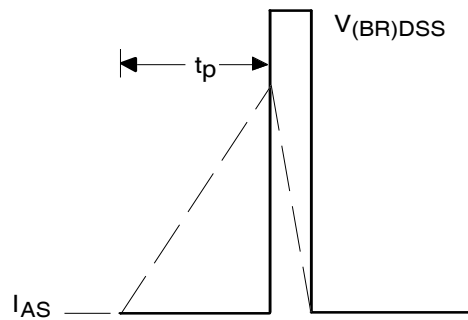
**Fig 13.** Maximum Avalanche Energy Vs. Drain Current



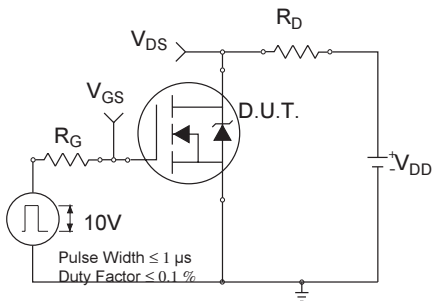
**Fig 14.** Diode Reverse Recovery Test Circuit for HEXFET® Power MOSFETs



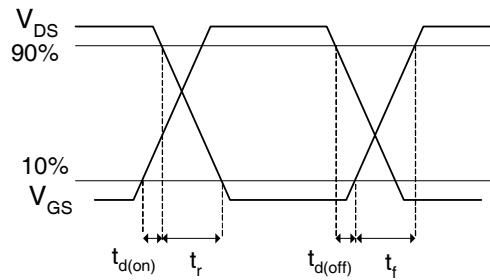
**Fig 15a.** Unclamped Inductive Test Circuit



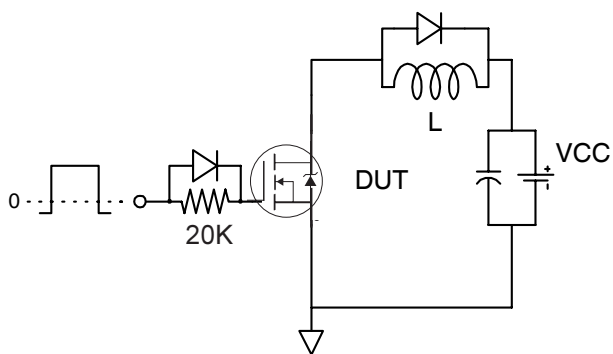
**Fig 15b.** Unclamped Inductive Waveforms



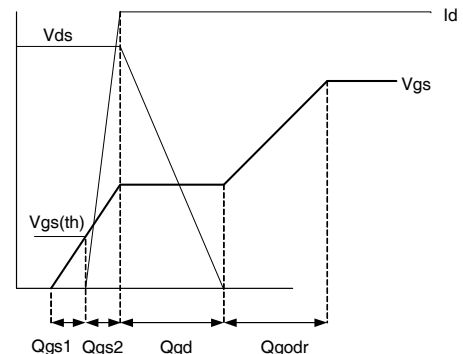
**Fig 16a.** Switching Time Test Circuit



**Fig 16b.** Switching Time Waveforms



**Fig 17a.** Gate Charge Test Circuit



**Fig 17b** Gate Charge Waveform



Note: For the most current drawings please refer to the IR website at:  
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